

63X_1_4_585

Microscope info:

| Image | | Image6_bead0 | | | | | | |
|----------------------------------|----------------------|-----------------------------|-------------|------------|-----------------------|----------------------|---------------------|--|
| image's date 2024-10-17 10:22:32 | | | | | | | | |
| creation | method used | sed from file creation date | | | | | | |
| Actual image depth | | 16 | | | | | | |
| Microscope type | | WideField | | | | | | |
| | NA | 1.4 | | | | | | |
| Objective | im. refractive index | 1.518 | | | | | | |
| | | Wavel | engths | | sampling (X,Y,Z) | | | |
| Channel(s) | | Ex. (nm) | Em. (nm) | Saturation | Nyquist (µm) | Found (µm) | Nyquist/found ratio | |
| Channel 0 | | | 585.0 | none | 0.104x0.104x0. 314 | 0.063x0.063x0. 06 | 0.6, 0.6, 0.2 | |
| Bead original pix | 1040.0, | 880.0 | | | | | | |

Warnings:

(No saturated pixels detected). (All channels sampled following Shannon-Nyquist criterion). (A subresolution bead is used for all channels).

Resolution table:

| Channel | Sig/Backgn d ratio | Dimension | Measured FWHM (µm) | theory (µm) | Fit Goodness | Mes./theory ratio |
|----------------------------|-----------------------|-----------|--------------------------|-------------|-----------------|-------------------|
| Channel 0 (em. 585.0nm) | 6.7 | X | 0.271 | 0.213 | 0.99 | 1.27 |
| | | Υ | 0.278 | 0.213 | 0.99 | 1.31 |
| | | Z | 0.677 | 0.802 | 0.98 | 0.84 |

Green: within specifications, red: outside specifications (ie. XY ratios above 1.5 or Z ratio above 2.0)

Lateral asymmetry ratios:

| Channel | Ratio |
|-------------------------|-------|
| Channel 0 (em. 585.0nm) | 0.97 |

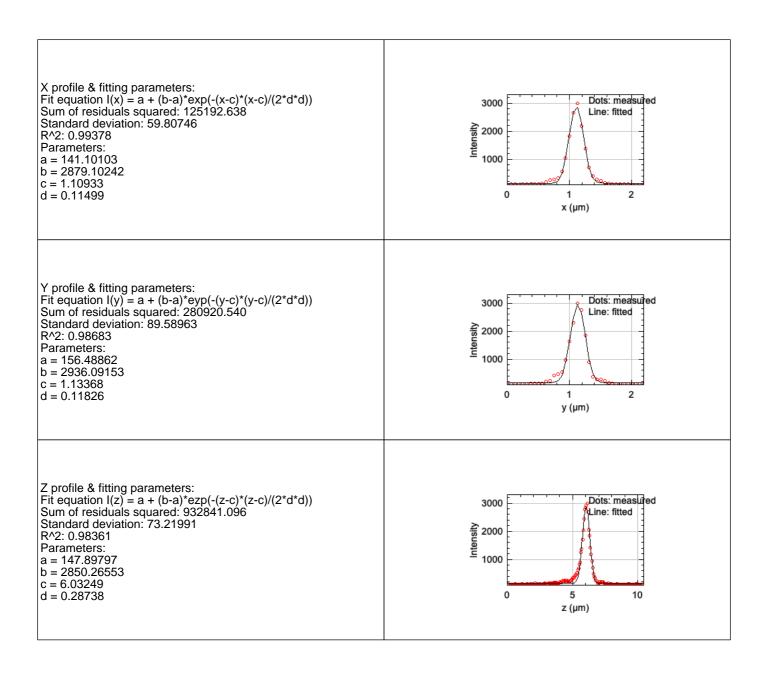
Detailed channel detection info:

Channel #0





| Channel 0 (em. 585.0nm) | | | | | |
|-------------------------|------|--------------|-------|------|--|
| Sig./Backgnd ratio | LAR | Fit goodness | | | |
| | | X | 0.271 | 0.99 | |
| 6.7 | 0.97 | Υ | 0.278 | 0.99 | |
| | | Z | 0.677 | 0.98 | |



Analysis parameters

| | Tool | PSF Profiler (batch) | | | |
|---------------------------------|--|---|--|--|--|
| Tool & Operator | Versions | MetroloJ_QC v1.3.1.1, ImageJ v2.14.0/1.54f, Java v1.8.0_322, OS Mac OS X | | | |
| | Operator & date | SO, October 25, 2024 2:32 PM | | | |
| data | result folder | /Users/oggsc/Documents/OM/ImageAnalysis/QC/Elyra/PSFs/20241014/63X_1_4/585//Processed/63X_1_4_585/Image6/bead0/ | | | |
| data | Type of saved data | .pdf, .jpg, .xls | | | |
| | Input data bit depth | 16 | | | |
| Dim | ension order | XY-(C)Z | | | |
| Discard s | aturated samples | false | | | |
| | Bead detection threshold | Legacy | | | |
| | Center detection method | Legacy Maximum Intensity | | | |
| | Discard bead if more than one particle are thresholded | true | | | |
| | Background annulus thickness in µm | 0.5 | | | |
| Beads | Background annulus distance to bead edges in µm | 0.5 | | | |
| Deads | Multiple beads in image | true | | | |
| | Bead identification method | Using Find Maxima (prominence of 1000.0) | | | |
| | Bead size (µm) | 0.1 | | | |
| | Bead crop Factor | 5.0 | | | |
| | Cropped ROI size in µm | 2.31x2.31 (using bead size & background annulus parameters) | | | |
| | Bead rejection distance to top/bottom | 2.0 μm | | | |
| Square Root PSF Image displayed | | true | | | |
| | Applied in this report | true | | | |
| Tolerance | X & Y FWHM ratios valid if below | 1.5 | | | |
| | Z FWHM ratio valid if below | 2.0 | | | |

Analysis log

| image name | creation date | saturation | sampling density | status |
|---------------|------------------------|------------|------------------|----------|
| Image 6_bead0 | 2024-10-17 10:22:32 | none | correct | analysed |

Formulas used:

Lateral $(res_{x,y}^o)$ and axial (res_z^o) theoretical resolution values used for widefield microscopes are calculated as defined in Wilhelm, S. Confocal Laser Scanning Microscopy, 2011:

$$res_{x,y}^o = \frac{0.51*\lambda_{em}}{NA}$$
 $res_z^o = \frac{1,77n*\lambda_{em}}{NA^2}$

NA: numerical aperture, λ_{em} : emission wavelength, n: refractive index of the lens immersion & mounting media.

Axis profiles are fitted using ImageJ Gaussian Curve Fitter and the following formula $y = a + (b - a) * e^{\frac{-(x-c)^2}{2d^2}}$ (Gaussian fitting).

Measured lateral and axial resolution (Full Width at Half Maximum, FWHM) values are derived using FWHM = $2d\sqrt{2ln(2)}$

Compliance with the Shannon-Nyquist criterion uses the following formulas for Shannon-Nyquist distances calculation:

$$\alpha = \arcsin(\frac{NA}{n})$$

$$\Delta_{x,y} = \frac{\lambda_{em}}{4.NA} \qquad \Delta_z = \frac{\lambda_{em}}{2.n. (1-\cos{(\alpha)})}$$